

UTC UNISONIC TECHNOLOGIES CO., LTD

7N70-R

Preliminary

Power MOSFET

7A, 700V N-CHANNEL POWER MOSFET

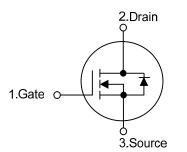
DESCRIPTION

The UTC 7N70-R is a high voltage power MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

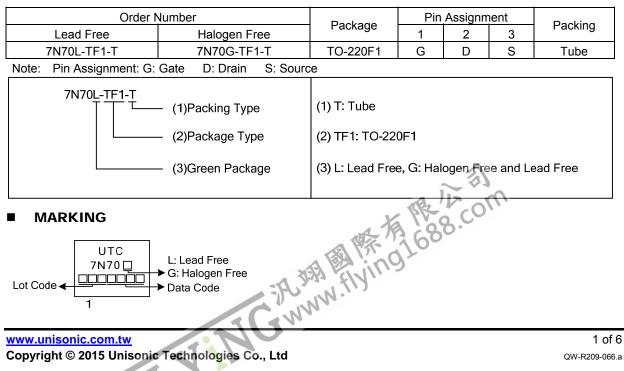
FEATURES

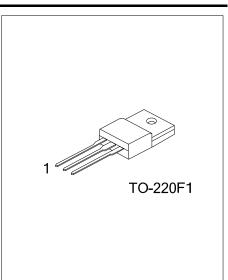
- * $R_{DS(ON)}$ < 1.4 Ω @ V_{GS} = 10V, I_D = 3.5A
- * Fast switching capability
- * Avalanche energy specified
- * Improved dv/dt capability, high ruggedness

SYMBOL



ORDERING INFORMATION





■ ABSOLUTE MAXIMUM RATINGS (T_c = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V _{DSS}	700	V	
Gate-Source Voltage		V _{GSS}	±30	V	
Continuous Drain Current	T _C = 25°C	- I _D	7.0	А	
	T _C = 100°C		4.7	А	
Drain Current Pulsed (Note 2)		I _{DM}	28	А	
Avalanche Energy, Single Pulsed (Note 3)		E _{AS}	490	mJ	
Avalanche Energy, Repetitive, Limited by T _{JMAX}		E _{AR}	14.2	mJ	
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.5	V/ns	
Power Dissipation ($T_c = 25^{\circ}C$)		PD	48	W	
Junction Temperature		TJ	+150	°C	
Storage Temperature		T _{STG}	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

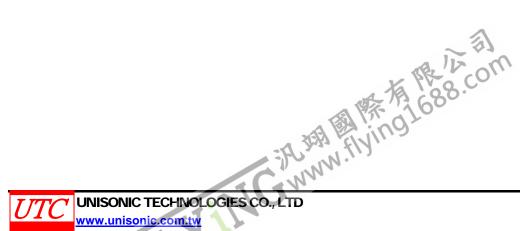
2. Repetitive Rating : Pulse width limited by T_J

3. L=20mH, I_{AS} =7.0A, V_{DD} =50V, R_G =0 Ω , Starting T_J =25°C

4. $I_{SD} \le 7.0A$, di/dt $\le 100A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting T_J=25°C

THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ _{JA}	62.5	°C/W
Junction to Case	θ _{JC}	2.6	°C/W



■ ELECTRICAL CHARACTERISTICS (T_c =25°C, unless otherwise specified)

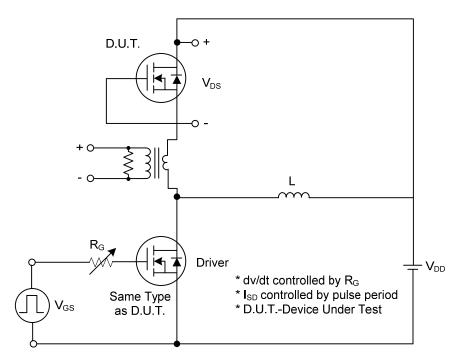
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	$V_{GS} = 0V, I_{D} = 250 \mu A$	700			V
Drain Source Leakage Current		V _{DS} = 700V, V _{GS} = 0V			1	μA
Drain-Source Leakage Current	I _{DSS}	V _{DS} = 560V, T _C = 125°C			1	μA
Cate Source Lookage Current	d L	$V_{GS} = 30V, V_{DS} = 0V$			100	nA
Gate-Source Leakage Current Reverse	e I _{GSS}	V_{GS} = -30V, V_{DS} = 0V			-100	nA
Breakdown Voltage Temperature Coefficie	ent $\triangle BV_{DSS} / \triangle T_J$	I _D = 250mA Referenced to 25°C		0.67		V/°C
ON CHARACTERISTICS					I	
Gate Threshold Voltage	V _{GS(TH)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
Drain-Source ON-State Resistance	R _{DS(ON)}	V _{GS} = 10V, I _D = 3.5A			1.4	Ω
Forward Transconductance (Note 1)	g _{FS}	V _{DS} = 40V, I _D = 3.5A		8.0		S
DYNAMIC CHARACTERISTICS			•			
Input Capacitance	C _{ISS}	V _{DS} = 25V, V _{GS} = 0V, f = 1MHz		750		pF
Output Capacitance	C _{OSS}			100		pF
Reverse Transfer Capacitance	C _{RSS}			13		pF
SWITCHING CHARACTERISTICS			•			
Turn-on Delay Time	t _{D(ON)}			78		ns
Turn-on Rise Time	t _R	$V_{DD} = 30V, I_D = 0.5A$		74		ns
Turn-off Delay Time	t _{D(OFF)}	RG=25Ω, V _{GS} =10V (Note 1, 2)		218		ns
Turn-off Fall Time	t _F			63		ns
Total Gate Charge	Q _G			33		nC
Gate-Source Charge	Q _{GS}	$V_{DS} = 50V, I_D = 1.3A,$		8.6		nC
Gate-Drain Charge	Q _{DD}	V _{GS} = 10V (Note 1, 2)		8.3		nC
SOURCE- DRAIN DIODE RATINGS AND	CHARACTERIS	TICS		_		
Drain-Source Diode Forward Voltage	V _{SD}	V _{GS} = 0V, I _S =7.0A			1.4	V
Maximum Continuous Drain-Source Diode	e				7.0	٨
Forward Current	Is				7.0	A
Maximum Pulsed Drain-Source Diode	lau.				28	А
Forward Current	I _{SM}				20	~
Reverse Recovery Time	t _{rr}	$V_{GS} = 0V, I_{S} = 7.0A,$		320		ns
Reverse Recovery Charge	Q _{RR}	dI _F /dt = 100 A/µs (Note 1)		2.4		μC

Notes: 1. Pulse Test: Pulse width \leq 300µs, Duty cycle \leq 2%

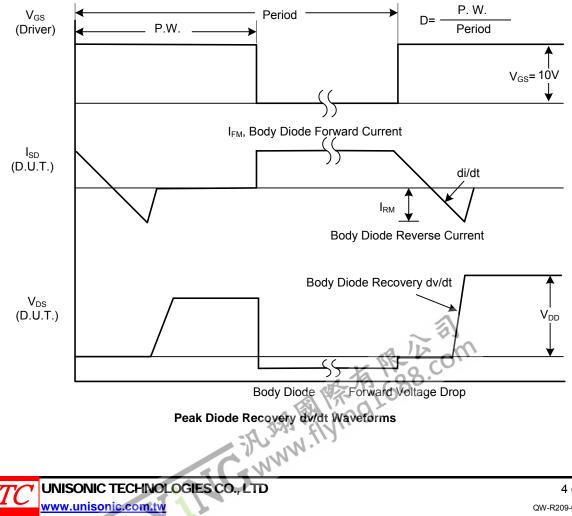
2. Essentially independent of operating temperature



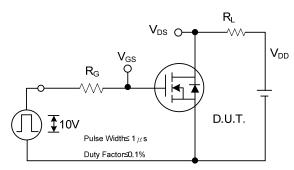
TEST CIRCUITS AND WAVEFORMS



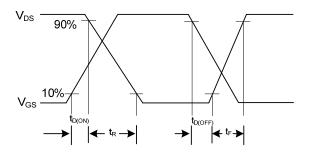
Peak Diode Recovery dv/dt Test Circuit



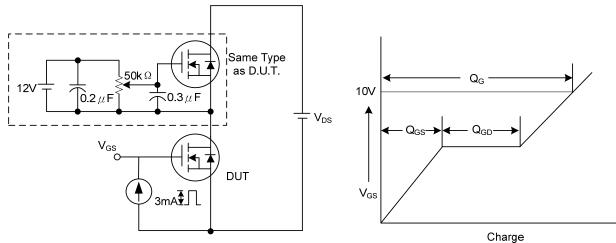
TEST CIRCUITS AND WAVEFORMS (Cont.)



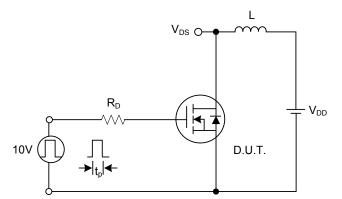




Switching Waveforms

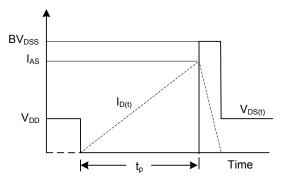


Gate Charge Test Circuit



Unclamped Inductive Switching Test Circuit

Gate Charge Waveform



-REALER PARTIES IN THE COM Unclamped Inductive Switching Waveforms

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